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			U.S. PATENT	DOCUMENTS	
Examiner Initials*	Cite No.1	Document Number  Number - Kind Code <sup>2</sup> (f known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
35	1	US-3,936,800	2/1976	Ejiri et al.	
1		US-4,115,702	9/1978	Nopper	
		US-4.115.762	9/1978	Akiyama et al.	1
		US-4,183,013	1/1980	Agrawala et al.	1
		US-4,200,861	4/1980	Hubach et al.	1
	$\top$	US-4,441,248	4/1984	Sherman et al.	1
		US-4,570,180	2/1986	Baier et al.	1
		US-4,685,143	8/1987	Choate	
		US-4.688.088	8/1987	Hamazaki et al.	
	$\top$	US-4.736.437	4/1988	Sacks et al.	
$\neg$		US-4,763,280	8/1988	Robinson et al.	
		US-4,783,826	11/1988	Koso	
		US-4.860.374	8/1989	Murakami et al.	
		US-4,876,457	10/1989	Bose	1
		US-4.876.728	10/1989	Roth	1
	$\neg$	US-4.922.543	5/1990	Ahlborm et al.	1
<u>†</u> i		US-4,955,062	9/1990	Terui	
		US-4,959,898	10/1990	Landman et al.	
		US-5,621,807	4/1997	Eibert et al.	
	$\neg \neg$	US-5,625,715	4/1997	Trew et al.	† · · · · · · · · · · · · · · · · · · ·
		US-5,627,912	5/1997	Matsumoto	
		US-5,627,915	5/1997	Rosser et al.	1.
	_	US-5.663.809	9/1997	Mivaza et al.	
		US-5,828,769	10/1998	Burns	†
		US-5,845,288	12/1998	Syeda-Mahmood	
		US-5.086.478	2/1992	Kelly-Mahaffey et al.	
		US-4,980,971	1/1991	Bartschat et al.	
		US-5,060,276	10/1991	Morris et al.	1
		US-5,113,565	5/1992	Cipolla et al.	1
		US-5,226,095	7/1993	Okumura et al.	
	$\top$	US-5,268,999	12/1993	Yokovama	
		US-5.343.028	8/1994	Figarella et al.	1
	77	US-5,371,690	12/1994	Engel et al.	
	11	US-5,471,541	11/1995	Burtnyk et al.	1
	$\top$	US-5,495,537	2/1996	Bedrosian et al.	
	1	US-5,497,451	3/1996	Holmes	<del>                                     </del>
1	$\neg \neg$	US-5,500,906	3/1996	Picard et al.	
1 1	$\neg \neg \neg$	US-5,545,887	8/1996	Smith et al.	<del>                                     </del>
4	1	US-5.602.937	2/1997	Bedrosian et al.	<u> </u>

	FOREIGN PATENT DOCUMENTS							
Examiner Initials*	Cite No.1	Foreign Patent Document  Country Code <sup>3</sup> - Number <sup>4</sup> - Kind Code <sup>5</sup> (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	7°		
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Sheet

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	NON PATENT LITERATURE DOCUMENTS						
Examiner Initials*	Cite No.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T²				
JS	_	GDALYAHU Y ET AL.: "Self-Organization in Vision: Stochastic Clustering for Image Segmentation, Perceptual Grouping, and Image Database Organization: IEEE Transactions on Pattern Analysis and Machine Intelligence, IEEE Inc. New York, Vol. 23, no. 10, October 2001, pages 1053-1074					
		PAUWELS E J ET AL: Finding Salient Regions in Images – Nonparametric Clustering for Image Segmentation and Grouping" Computer Vision and Image Understanding, Academic Press, San Diego, CA, Vol. 75, no. 1-2, July 1999, pages 73-85	-				
	1	SCANLON J. ET AL.: Graph-theoretic Algorithms for Image Segmentation, Circuits and Systems, 1999, ISCAS '99. Proceedings of the 1999 IEEE International Symposium, Orlando, FL, May 30,1999, pages 141-144					
		JIANBO SHI ET AL: Normalized Cuts and Image Segmentation, Computer Vision and Pattern Recognition, 1997. Proceedings, 1997 IEEE Computer Society Conference, San Juan, Puerto Rico 17-19 June 1997, pages 731-737					
	/	XIE X L ET AL. A new fuzzy clustering validity criterion and its application to color image segmentation, Proceedings of the International Symposium on Intelligent Control, Arlington, Aug. 13 – 15, 1991, pages 463-468					
	_	MEHROTRA R ET AL: Feature-based retrieval of similar shapes, Proceeding of the International Conference on Data Engineering. Vienna, April 19 – 23, 1993, pages 108-115	_				
	)	COGNEX CORPORATION, Cognex MVS-8000 Series, CVL Vision Tools Guide, pp. 25-136, Release 5.4 590-6271, Natick, MA USA 2000	)				
		Hoogs et al., "Model-Based Learning of Segmentations", IEEE, pp. 494-499, 1996					
	1	Medina-Mora, R., "An Incremental Programming Environment," IEEE <i>Transactions on Software Engineering</i> , September 1981, pp. 472-482, Vol. SE-7, No. 5, 1992					
		Newman et al., "3D CAD-Based Inspection I: Coarse Verification", IEEE, pp. 49-52, 1992					
	(	Ullman, S., "Aligning pictorial descriptions: An approach to object recognition, I: Approaches to Object Recognition," reprinted from <i>Cognition</i> , pp. 201-214, Volume 32, No. 3, Cambridge, MA USA, August 1989					
U		deFigueiredo et al. "Model Based Orientation Independent 3-D Machine Vision Techniques, IEEE Transactions on Aerospace and Electronic Systems, vol. 24, No. 5 Sept 1988, pp.597-607					

Examiner Date Signature Considered

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Substitute for form 1449APTO INFORMATION DISCLOSURE STATEMENT BY APPLICANT	Complete If Known			
(Use as many sheets as necessary)	Application Number	10/625,201		
DIPE 40	Filing Date	July 22, 2003		
0112 4014	First Named Inventor	Davis, Jason		
JUL 2 2 2005 \$	Group Art Unit			
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Sheet 1 of 2	Attorney Docket No: Co	03-002		

			US PATEN	IT DOCUMENTS	
Examiner Initial *	Cite No. *	USP Document Number	Publication Date	Name of Patentee or Applicant of cited Document	Pages,Columns,Lines,Where Relevant Passages or Relevant Figures Appear
ک (		US-5,933,516	08/03/1999	Tu, Peter H., et af.	
35		US-US2002/0054699A1	05/09/2002	Roesch, Peter, et al.	

		FO	REIGN PAT	ENT DOCUMENTS		
Examiner Initials*	Cite No. *	Foreign Document No Country Code - Number - Kind Code (if known)	Publication Date	Name of Patentee or Applicant of cited Document	Pages,Columns,Lines, Where Relevant Passages or Relevant Figures Appear	T <sup>2</sup>
		DE-DE 44 06 020	06/29/1995	Konen, Wolfgang , et al.		

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<i>J.</i>	ς	Ì	BELONGIE, S., et al., "Shape Matching and Object Recognition Using Shape Contexts", <u>IEEE Transactions on Pattern Analysis and Machine Intelligence, IEEE Inc.</u> New York, Vol. 24, No. 4, (April, 2003),509 - 522	
		. )	BILESCHI, S., et al., "Advances in Component-based Face Detection", <u>Lecture notes</u> in Computer Science, Springer Verlag, New York, NY, Vol. 2388, (2002),135 - 143	
		1	BOOKSTEIN, F L., "Principal Warps: Thin-Plate Splines and the Decomposition of Deformations", IEEE Transactions on pattern Analysis and Machine Intelligence, IEEE Inc., New York, Vol. 11, No. 6,(6/1/1989),	^
		`	FITZPATRICK, J M., et al., "Handbook of Medical Imaging", <u>Vol. 2: Medical image</u> <u>Processing and Analysis.</u> SPIE Press, Bellingham, WA,(2000),447-513	_

EXAMINER DATE CONSIDERED 3/1/07

EXAMINER: Initial if reference considered, whether or not distion is in conformence with MPEP 600. Draw the art through cluster is not consume and not considered, include copy of this form with next communication to applicant. I Applicant's unique citation designation number (optionally a Applicant is to tipsoe a check mark here if English tanguage Transittion is establed.

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Substitute for form 1449A/PTO INFORMATION DISCLOSURE STATEMENT BY APPLICANT	Complete if Known	
(Use as many sheets as necessary)	Application Number	10/625,201
OIPE	Filing Date	July 22, 2003
G. G. G.	First Named Inventor	Davis, Jason
JUL 2 2 2005	Group Art Unit	0
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Sheet 2 of 2	Attorney Docket No: Co	03-002

	OTHER DOCUMENTS NON PATENT LITERATURE DOCUMENTS				
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15	)		OHM, JENS-RAINER, "Digitale Bildcodierung", <u>Springer Verlag, Berlin 217580, XP0002303066.</u> Section 6.2 Bewegungschatzung,(1995),		
		_	STOCKMAN, G, et al., "Matching images to models for registration and object detection via clustering", IEEE Transaction of Pattern Analysis and Machine Intelligence, IEEE Inc., New York, Vol. PAMI-4, No. 3,,(1982),		
			WEI, WEN, et al., "Recognition and Insprection of Two-Dimensional Industrial Parts Using Subpolygons", Pattern Recognition, Elsevier, Kidlington, GB, Vol. 25, No. 12, (12/1/1992),1427 - 1434		
d		_	ZHANG, ZHENGYOU, "Parameter estimation techniques: A tutorial with application to conic fitting", <u>Imag Vision Comput; Image and Vision computing; Elsevier Science Ltd, Oxford England,</u> Vol. 15, No. 1,(1/1/1997),		

EXAMINER DATE CONSIDERED 3/1/07

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